



Sensors for Precision Dimensional Metrology

Guest Editor:

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Deadline for manuscript
submissions:

closed (31 October 2019)

Message from the Guest Editor

Dear Colleagues,

The aim of this Special Issue is to bring together researchers active in the research, development, calibration and characterization of sensors that are applied in dimensional metrology in order to achieve the highest accuracy and thus the lowest uncertainty.

In the continuous development towards higher speed, lower cost, more data, smaller acquisition times, better traceability, less user intervention, more autonomous systems, the development, characterization and calibration of sensors is even more imperative than before.

I cordially invite you to share your work, expertise and insights, with the dimensional measurement and calibration community, in the form of research articles and reviews.

- Sensor
- XCT
- Interferometry
- Digital Holography
- Capacitive sensor
- LVDT
- Calibration
- Traceability
- Chromatic confocal sensor





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CiteScore (2018 Scopus data): **3.72**; ranked 9/123 in 'Physics and Astronomy: Instrumentation' and 102/661 in 'Electrical and Electronic Engineering'.

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